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<u>EE 105</u>: Microelectronic Devices & Circuits <u>Lecture 24w</u>: High Frequency Small-Signal Models

 $C_{\mu} = \frac{C_{\mu o}}{\sqrt{1 + \frac{V_{CB}}{O_i}}}$ (for an abrupt junction) Where Cuo² Capacitance for Vcg=OV Øj = built-in potential between pin type somiconductors $= \frac{kT}{2} ln \left(\frac{N_{aB} N_{dC}}{N^2} \right) ; N_{i} = 1.45 \times 10^{10} cm^3$ More generally: Cu: <u>Cuo</u> CJC in SPICE MJC in SPICE UJC in SPICE (1+ VCB) m; m= fcn of junction interface We assume this (=1/2 for abrupt) CIT - Base-to-Emitter Capacitonce ⇒ two components comprise Crr: () Junction Capacitonia, Cje (2) Diffusion Capacitane, Ch



=) switch to small-signal parameters: - Small -sigh a verige 9= Tric Cb= q== TF Ac = TFgm= TF · CLAIN Putting it all together. $C_{\Pi} = C_b + C_j e = T_F g_m + \frac{C_j e \sigma}{I + V_0}$ Determining CIT and CM Can experimentally determine C_{μ} by measuring the small-signal capacitance between the base and collector terminals with the emitter incrementally open, i.e., use a current source to set I_F imposed by Capacitance ven J'c 10 Vca S.S.CH Mezgi TCT 9m Vbo δE small-signal open ⇒ can measure CM VS. VCB



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